

Notice of References Cited	Application/Control No. 10/701,871	Applicant(s)/Patent Under Reexamination GUO ET AL.	
	Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,866,845	03-2005	Ward et al.	424/139.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 245 993	11-1987	Europe	Larrick et al.	
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	T					

NON-PATENT DOCUMENTS

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	U	Huber-Lang et al. The FASEB J. 16: 1567-1574, October 2002.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.